



FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE		ATTY. DOCKET NO. S00-086/US		SERIAL NO. 09/925,278	
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Subbhasish Mitra	
				FILING DATE 8/8/2001	
U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	RELEVANT INFORMATION
	A				
FOREIGN PATENT DOCUMENTS					
	2- letter code	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION
					YES NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)					
	B	[De Sousa 78] De Sousa, P.T., and F.P. Mathur, "Sift-Out-Modular Redundancy," IEEE Trans. Computers, Vol. C-27, No. 7, pp. 624-627, July 1978			
	C	[Dennis 74] Dennis, N. G., "Ultra-reliable Voter Switches with a Bibliography of Mechanization," Microelectronics and Reliability, pp. 299-308, August 1974			
	D	[Gersting 91] Gersting, J. L., et al., "A Comparison of Voting Algorithms for N-Version Programming," Proc. Annual Hawaii Intl. Conf. on System Sciences, pp. 253-262, 1991.			
	E	[Lala 94] Lala, J. H. and R. E. Harper, "Architectural Principles for Safety-critical Real-time Applications," Proc. of the IEEE, Vol. 82, No. 1, pp. 25-40, Jan. 1994.			
	F	[Mitra 99] Mitra, S., N. R. Saxena and E. J. McCluskey, "A Design Diversity Metric and Reliability Analysis for Redundant Systems," Proc. Intl. Test Conf., pp. 662-671, 1999.			
	G	[Mitra 00] Mitra, S., and E. J. McCluskey, "Design of Redundant Systems Protected Against Common-Mode Failures," Technical Report, Center for Reliable Computing, Stanford Univ., CRC-TR-00-2, 2000. (http://crc.stanford.edu)			
	H	[Reed 97] Reed, R., et al., "Heavy Ion and Proton-Induced Single Event Multiple Upset," IEEE Trans. on Nuclear Science, Vol. 44, No. 6, pp. 2224-2229, July 1997.			
	I	[Siewiorek 75] Siewiorek, D. P., "Reliability Modeling of Compensating Module Failures in Majority Voted Redundancy," IEEE Trans. Computers, Vol. 24, No. 5, pp. 525-533, 1975.			
	J	[Siewiorek 92] Siewiorek, D. P. and R. S. Swarz, <i>Reliable Computer Systems: Design and Evaluation</i> , Digital Press, 1992.			
	K	[TI 76] <i>The TTL Data Book</i> , Texas Instruments, 1976			
	L	[Trivedi 82] Trivedi, K.S., <i>Probability and Statistics with Reliability, Queuing, and Computer Science Applications</i> , Prentice Hall, Englewood Cliffs, NJ, USA, 1982.			
	M	[Von Neumann 56] Von Neumann, J., "Probabilistic Logics and the Synthesis of Reliable Organisms from Unreliable Components," <i>Automata Studies, Ann. of Math. Studies</i> , no. 34, C. E. Shannon and J. McCarthy, Eds., Princeton University Press, pp. 43-98, 1956.			

	N	[Wong 96] Wong, K., et al., "A VLSI Median Voter for Fault Tolerant Signal Processing Applications," Proc. Intl. Conf. Signal Processing, pp. 1574-1577, 1996.
	O	[Shehata] et al. "Rapid Prototyping of High Performance DSP Architectures Targeting FPGAs" in a paper published with Concordia University, Dept. of Electrical and Computer Engineering.
EXAMINER		DATE CONSIDERED
R. Stephen Gilmore		2 May 2005
<p>* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>		